

M.2 (S80)

3SE2-P Series

AES Function

Customer: _____

Customer

Part

Number: _____

Innodisk

Part

Number: _____

Innodisk

Model Name: _____

Date: _____

Innodisk Approver	Customer Approver

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REVISION HISTORY

Revision	Description	Date
Pre.	First Released	May, 2019
Pre 1.1	Revised performance	July, 2019
Ver 1.0	Add caution notice and update REACH, RoHS	Aug, 2019
Ver 1.1	Update performance and power consumption data	Mar, 2020

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1. Product Overview

1.1 Introduction of Innodisk M.2 (S80) 3SE2-P with AES function

Innodisk M.2 (S80) 3SE2-P is designed as the standard M.2 form factor with SATA interface, and supports SATA III standard (6.0Gb/s) with excellent performance. The form factor refers to the M.2(NGFF) specification which established by JEDEC. Regarding of mechanical interference, Innodisk M.2 (S80) 3SE2-P absolutely replaces the traditional hard disk and makes personal computer, in any field, smaller and easier. Innodisk M.2 (S80) 3SE2-P is designed with AES engine, which is a built-in controller. When controller receives the data package from host, AES engine encrypts the data package and saves the encrypted data into NAND flash. Thus, unauthorized personal has no access to decrypt the data in NAND flash.

Innodisk M.2 (S80) 3SE2-P effectively reduces the booting time of operation system and the power consumption is less than hard disk drive (HDD), and complies with ATA protocol, no additional drives are required, and can be configured as a boot device or data storage device.

CAUTION *TRIM must be enabled.*

TRIM enables SSD's controller to skip invalid data instead of moving. It can free up significant amount of resources, extends the lifespan of SSD by reducing erase, and write cycles on the SSD. Innodisk's handling of garbage collection along with TRIM command improves write performance on SSDs

1.2 Product View and Models

Innodisk M.2 (S80) 3SE2-P is available in follow capacities within SLC flash ICs. 3SE2-P is followed M.2 2280-D2-B-M standard.

M.2 (S80) 3SE2-P 8GB	M.2 (S80) 3SE2-P 64GB
M.2 (S80) 3SE2-P 16GB	M.2 (S80) 3SE2-P 128GB
M.2 (S80) 3SE2-P 32GB	M.2 (S80) 3SE2-P 256GB

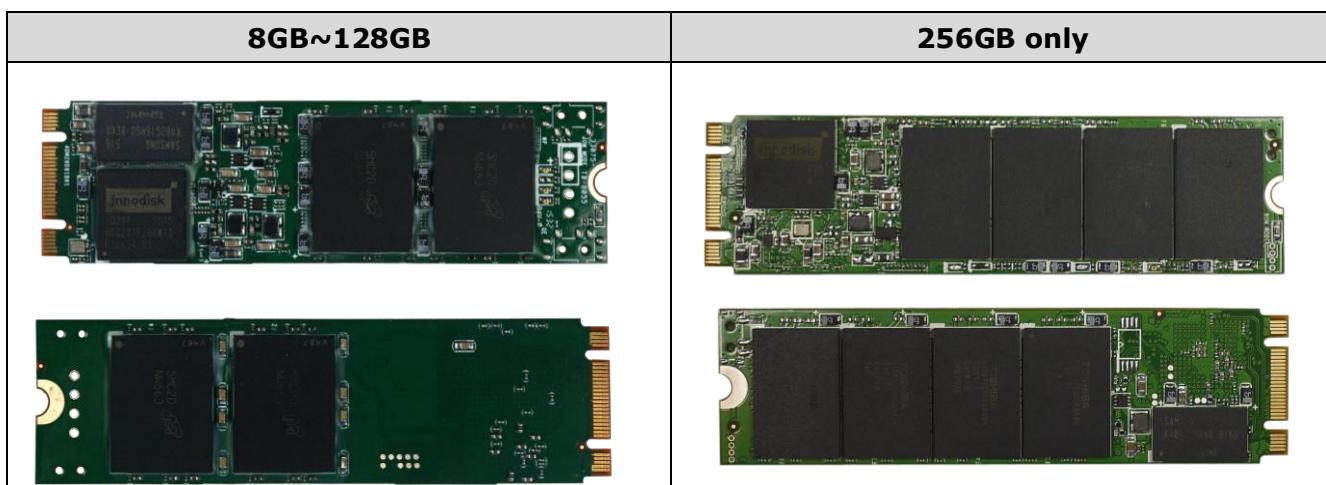


Figure 1: Innodisk M.2 (S80) 3SE2-P (type 2280)

1.3 SATA Interface

Innodisk M.2 (S80) 3SE2-P supports SATA III interface, and compliant with SATA I and SATA II. SATA III interface can work with Serial Attached SCSI (SAS) host system, which is used in server computer. Innodisk M.2 (S80) 3SE2-P is compliant with Serial ATA Gen 1, Gen 2 and Gen 3 specification (Gen 3 supports 1.5Gbps /3.0Gbps/6.0Gbps data rate).

2. Product Specifications

2.1 Capacity and Device Parameters

M.2 (S80) 3SE2-P device parameters are shown in Table 1.

Table 1: Device parameters

Capacity	Cylinders	Heads	Sectors	LBA	user space
8GB	16383	16	63	14900256	7275
16GB	16383	16	63	30367744	14828
32GB	16383	16	63	61300736	29932
64GB	16383	16	63	123166720	60140
128GB	16383	16	63	246898688	120556
256GB	16383	16	63	494362624	241388

2.2 Performance

Burst Transfer Rate: 6.0Gbps

Table 2: Performance

Capacity	8GB	16GB	32GB	64GB	128GB	256GB
Sequential Read (QD32)*	240 MB/s	460 MB/s	520 MB/s	520 MB/s	520 MB/s	520 MB/s
Sequential Write (QD32)*	60 MB/s	120 MB/s	240 MB/s	330 MB/s	340 MB/s	340 MB/s
4KB Random Read (QD32)*	33,700 IOPS	65,000 IOPS	74,000 IOPS	76,000 IOPS	76,000 IOPS	76,000 IOPS
4KB Random Write (QD32)*	15,800 IOPS	34,000 IOPS	65,000 IOPS	72,000 IOPS	75,000 IOPS	75,000 IOPS

Note: * Performance is based on CrystalDiskMark 5.1.2 with file size 1000MB of Queue Depth 32

2.3 Electrical Specifications

2.3.1 Power Requirement

Table 3: Innodisk M.2 (S80) 3SE2-P Power Requirement

Item	Symbol	Rating	Unit
Input voltage	V _{IN}	+3.3 DC +- 5%	V

2.3.2 Power Consumption

Table 4: Power Consumption

Mode	Power Consumption (mA)
Peak	324 (max.)
Read	560 (max.)
Write	670 (max.)
Idle	110 (max.)

* Target: 256GB M.2 (S80) 3SE2-P AES

2.4 Environmental Specifications

2.4.1 Temperature Ranges

Table 5: Temperature range for M.2 (S80) 3SE2-P

Temperature	Range
Operating	Standard Grade: 0°C to +70°C
	Industrial Grade:-40°C to +85°C
Storage	-55°C to +95°C

2.4.2 Humidity

Relative Humidity: 10-95%, non-condensing

2.4.3 Shock and Vibration

Table 6: Shock/Vibration Testing for M.2 (S80) 3SE2-P

Reliability	Test Conditions	Reference Standards
Vibration	7 Hz to 2K Hz, 20G, 3 axes	IEC 68-2-6
Mechanical Shock	Duration: 0.5ms, 1500 G, 3 axes	IEC 68-2-27

2.4.4 Mean Time between Failures (MTBF)

Table 7 summarizes the MTBF prediction results for various M.2 (S80) 3SE2-P configurations. The analysis was performed using a RAM Commander™ failure rate prediction.

- **Failure Rate:** The total number of failures within an item population, divided by the total number of life units expended by that population, during a particular measurement interval under stated condition.
- **Mean Time between Failures (MTBF):** A basic measure of reliability for repairable items: The mean number of life units during which all parts of the item perform within their specified limits, during a particular measurement interval under stated conditions.

Table 7: M.2 (S80) 3SE2-P MTBF

Product	Condition	MTBF (Hours)
Innodisk M.2 (S80) 3SE2-P	Telcordia SR-332 GB, 25°C	>3,000,000

2.5 CE and FCC Compatibility

M.2 (S80) 3SE2-P conforms to CE and FCC requirements.

2.6 RoHS Compliance

M.2 (S80) 3SE2-P is fully compliant with RoHS directive.

2.7 Reliability

Parameter	Value	
Read Cycles	Unlimited Read Cycles	
Flash endurance	60,000 P/E cycles	
Wear-Leveling Algorithm	Support	
Bad Blocks Management	Support	
Error Correct Code	Support	
(Total Bytes Written) Unit:TB		
Capacity	Sequential workload	Client workload
8GB	426.1	187.5
16GB	852.3	375
32GB	1704.5	750
64GB	3409	1500
128GB	6818.2	3000
256GB	13636.4	6000
* Note: 1. Sequential: Mainly sequential write, tested by Vdbench. 2. Client: Follow JESD218 Test method and JESD219A Workload, tested by ULINK. (The capacity lower than 64GB client workload is not specified in JEDEC219A, the values are estimated.) 3. Based on out-of-box performance.		

2.8 Transfer Mode

M.2 (S80) 3SE2-P support following transfer mode:

Serial ATA III 6.0Gbps

Serial ATA II 3.0Gbps

Serial ATA I 1.5Gbps

2.9 Pin Assignment

Innodisk M.2 (S80) 3SE2-P uses a standard SATA pin-out. See Table 8 for M.2 (S80) 3SE2-P pin assignment.

Table 8: Innodisk M.2 (S80) 3SE2-P Pin Assignment

Signal Name	Pin #	Pin #	Signal Name
		75	GND
3.3V	74	73	GND
3.3V	72	71	GND
3.3V	70	69	GND
NC	68	67	NC
Notch	66	65	Notch
Notch	64	63	Notch
Notch	62	61	Notch
Notch	60	59	Notch
NC	58		
NC	56	57	GND
NC	54	55	NC
NC	52	53	NC
NC	50	51	GND
NC	48	49	RX+
NC	46	47	RX-
NC	44	45	GND
NC	42	43	TX-
NC	40	41	TX+
DEVSLP	38	39	GND
NC	36	37	NC
NC	34	35	NC
NC	32	33	GND
NC	30	31	NC
NC	28	29	NC
NC	26	27	GND
NC	24	25	NC
NC	22	23	NC
NC	20	21	GND
Notch	18	19	Notch
Notch	16	17	Notch
Notch	14	15	Notch
Notch	12	13	Notch
DAS/DSS	10	11	NC
NC	8	9	NC
NC	6	7	NC
3.3V	4	5	NC

3.3V	2	3	GND
		1	GND

2.10 Mechanical Dimensions

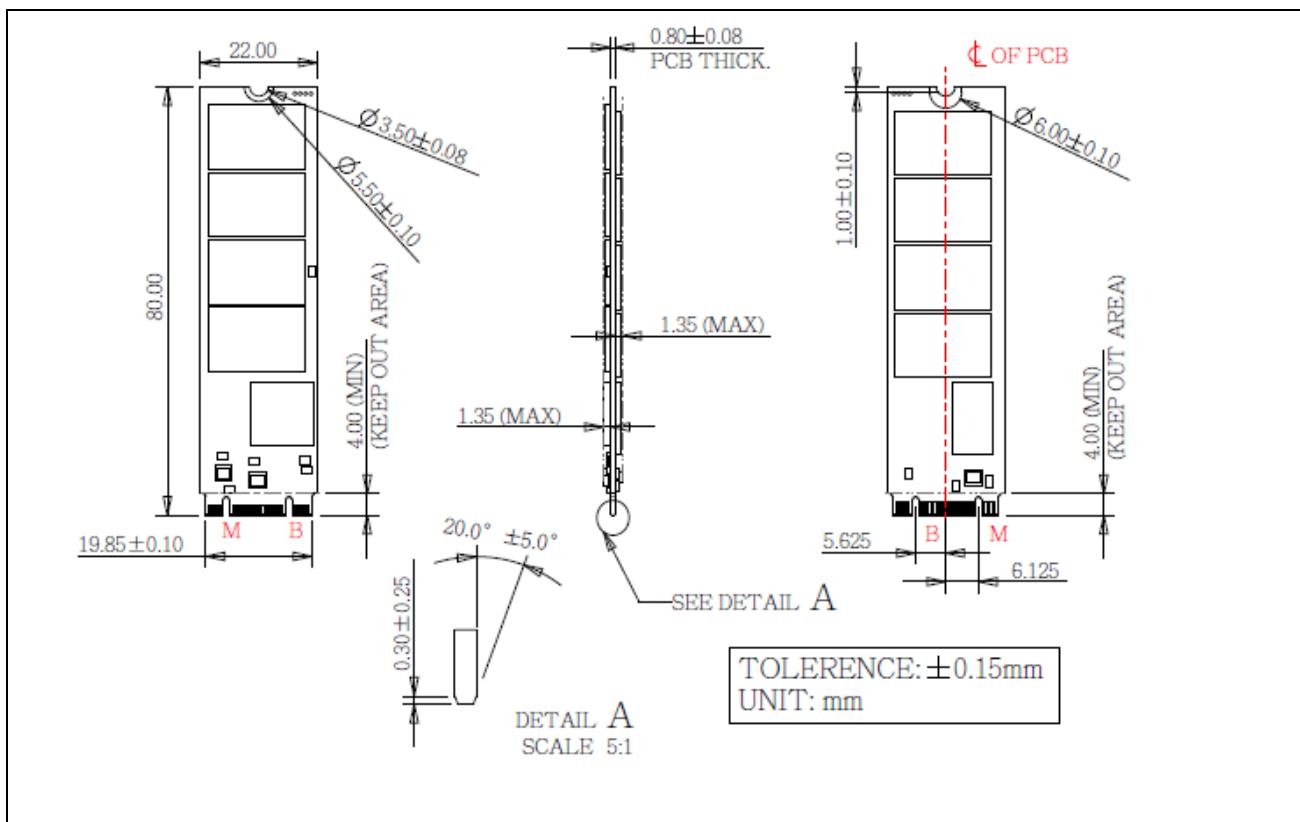


Figure 2: DEM28-B56D82SQC(256GB)**

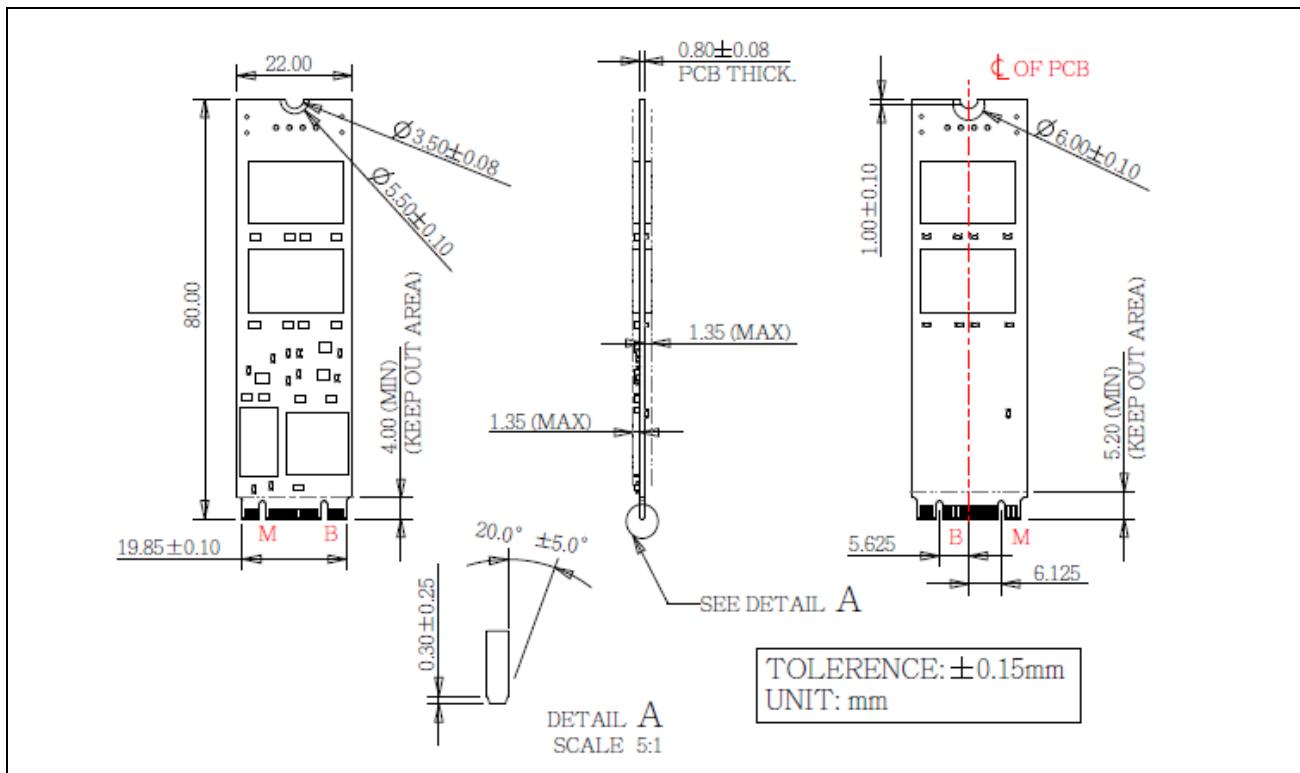


Figure 3: DEM28-*D82***** (8GB~128GB)**

2.11 Assembly Weight

An Innodisk M.2 (S80) 3SE2-P within flash ICs, 256GB's weight is 12 grams approximately.

2.12 Seek Time

Innodisk M.2 (S80) 3SE2-P is not a magnetic rotating design. There is no seek or rotational latency required.

2.13 Hot Plug

The SSD support hot plug function and can be removed or plugged-in during operation. User has to avoid hot plugging the SSD which is configured as boot device and installed operation system.

Surprise hot plug : The insertion of a SATA device into a backplane (combine signal and power) that has power present. The device powers up and initiates an OOB sequence.

Surprise hot removal: The removal of a SATA device from a powered backplane, without first being placed in a quiescent state.

2.14 NAND Flash Memory

Innodisk M.2 (S80) 3SE2-P uses Single Level Cell (SLC) NAND flash memory, which is non-volatility, high reliability and high speed memory storage.

3. Theory of Operation

3.1 Overview

Figure 4 shows the operation of Innodisk M.2 (S80) 3SE2-P from the system level, including the major hardware blocks.

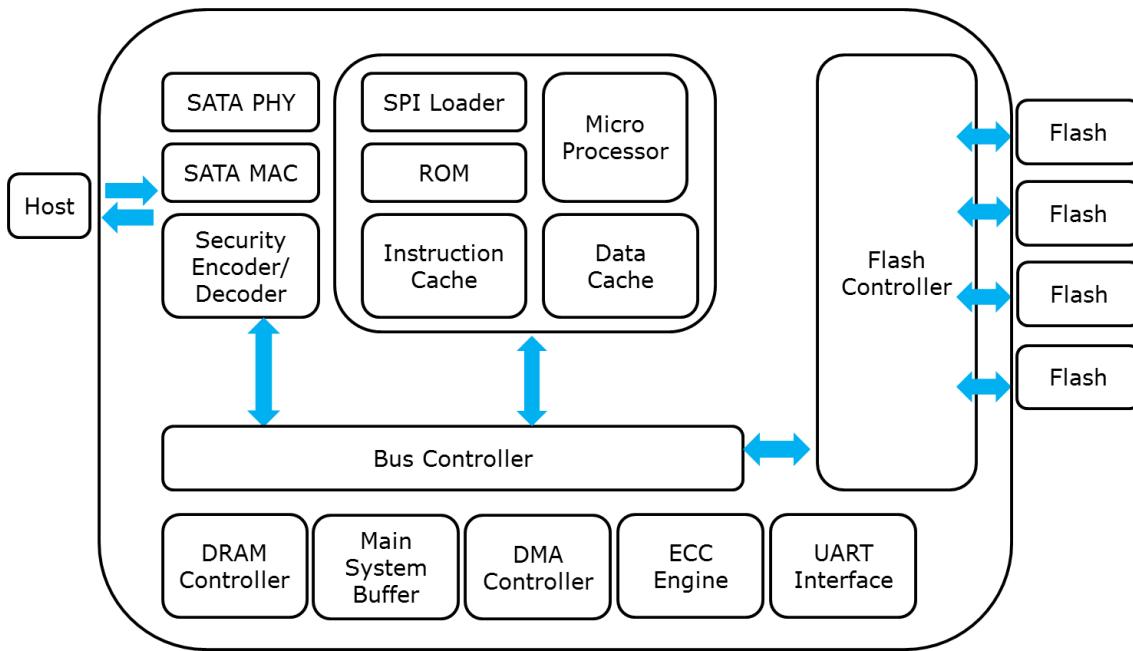


Figure 4: Innodisk M.2 (S80) 3SE2-P Block Diagram

Innodisk M.2 (S80) 3SE2-P integrates a SATA III controller and NAND flash memories. Communication with the host occurs through the host interface, using the standard ATA protocol. Communication with the flash device(s) occurs through the flash interface. The AES engine was built-in the ID201 controller. When M.2 (S80) 3SE2-P is initiated with Firmware, AES engine will generate a random number to be an AES key. Each SSD has a unique AES key when it leaves the factory.

3.2 SATA III Controller

Innodisk M.2 (S80) 3SE2-P is designed with ID201 built-in 256bits AES engine, a SATA III 6.0Gbps (Gen. 3) controller, which supports external DDR3 DRAM. The Serial ATA physical, link and transport layers are compliant with Serial ATA Gen 1, Gen 2 and Gen 3 specification (Gen 3 supports 1.5Gbps/3.0Gbps/6.0Gbps data rate). The controller has 4 channels for flash interface.

3.3 Error Detection and Correction

Highly sophisticated Error Correction Code algorithms are implemented. The ECC unit consists of the Parity Unit (parity-byte generation) and the Syndrome Unit (syndrome-byte computation).

This unit implements an algorithm that can correct 66 bits per 1024 bytes in an ECC block. Code-byte generation during write operations, as well as error detection during read operation, is implemented on the fly without any speed penalties.

3.4 Wear-Leveling

Flash memory can be erased within a limited number of times. This number is called the **erase cycle limit** or **write endurance limit** and is defined by the flash array vendor. The erase cycle limit applies to each individual erase block in the flash device.

Innodisk M.2 (S80) 3SE2-P uses a static wear-leveling algorithm to ensure that consecutive writes of a specific sector are not written physically to the same page/block in the flash. This spreads flash media usage evenly across all pages, thereby extending flash lifetime.

3.5 Bad Blocks Management

Bad Blocks are blocks that contain one or more invalid bits whose reliability are not guaranteed. The Bad Blocks may be presented while the SSD is shipped, or may develop during the life time of the SSD. When the Bad Blocks is detected, it will be flagged, and not be used anymore. The SSD implement Bad Blocks management, Bad Blocks replacement, Error Correct Code to avoid data error occurred. The functions will be enabled automatically to transfer data from Bad Blocks to spare blocks, and correct error bit.

3.6 iData Guard

Innodisk's iData Guard is a comprehensive data protection mechanism that functions before and after a sudden power outage to M.2. Low-power detection terminates data writing before an abnormal power-off, while table-remapping after power-on deletes corrupt data and maintains data integrity. Innodisk's iData Guard provides effective power cycling management, preventing data stored in flash from degrading with use.

3.7 Garbage Collection/TRIM

Garbage collection and TRIM technology is used to maintain data consistency and perform continual data cleansing on SSDs. It runs as a background process, freeing up valuable controller resources while sorting good data into available blocks, and deleting bad blocks. It also significantly reduces write operations to the drive, thereby increasing the SSD's speed and lifespan.

3.8 M.2 (S80) 3SE2-P AES function flow chart

In order to complete the physical security layer of protection, encryption needs to be paired with an ATA user password by ATA security command. After setting the authorized key by ATA security command, every time when you power on the system with SSD encrypted, you will be requested for a password to access the SSD. If the password is correct, the SSD will run well; if not, then you will not be able to access the SSD then.

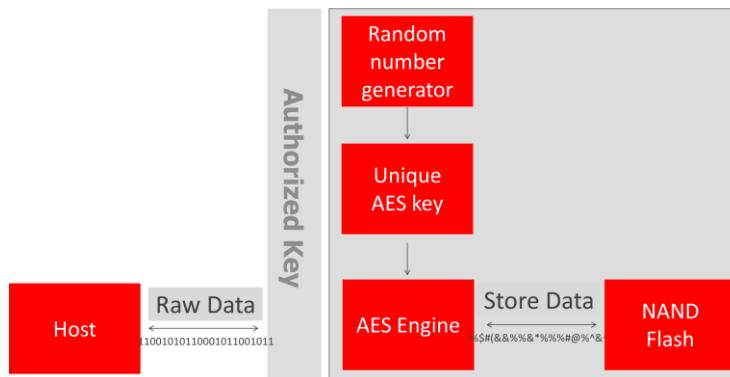


Figure 5: Innodisk M.2 (S80) 3SE2-P AES flow chart

3.8.1 Encrypted Key Management

Innodisk 3SE2-P SSD includes two methods of key management to apply to different applications. The first is a standard approach that allows the firmware to generate a random number and a unique key when it leaves the factory. This method ensures that the user can easily apply the SSD with the data encrypted key. Another approach is to meet unique customer requirements with an encrypted key generated by an SSD from the SATA interface host. The SSD must keep the encrypted key value when receiving the reset commands. This method works best for the SSD as a removable device in different systems. Innodisk provides the test tool to execute the AES hardware encryption. This user-friendly tool, developed by Innodisk Corporation, allows the customer to use/test encryption functions.

3.8.2 Authorized Key Management

In order to complete the physical security layer of protection, encryption needs to be bundled with an ATA user password provided by an ATA Security command. Unlike the AES key, the authorized key must be set by the user via the BIOS configuration. Every time you power on the system with SSD encryption, a password request prompt is sent to access the SSD. If the password is correct, the SSD will run well; if not, you will not be able to access the SSD.

Command	Command Code
SECURITY SET PASSWORD	0XF1
SECURITY UNLOCK	0XF2
SECURITY ERASE PREPARE	0XF3
SECURITY ERASE UNIT	0XF4
SECURITY FREEZE LOCK	0XF5
SECURITY DISABLE PASSWORD	0XF6

3.8.3 TCG OPAL

OPAL is a set of specifications for features of data storage devices that enhance security. These specifications are published by the Trusted Computing Group's Storage Work Group. Innodisk

3SE2-P is compliant with TCG OPAL 2.0(*1). The capability of TCG OPAL Security mode allows multiple users with independent access control to read/write/erase independent data areas (LBA ranges). Each locking range adjusts by authenticated authority. Note that by default there is a single "Global Range" that encompasses the whole user data area. In TCG Opal Security Mode, Revert, Revert SP and GenKey command can erase all of data including global range and locking range; in the meantime generate the new encrypted key.

*1. You need to install TCG OPAL software to implement OPAL function, which is supplied by TCG OPAL software developed company

4. Installation Requirements

4.1 M.2 (S80) 3SE2-P Pin Directions

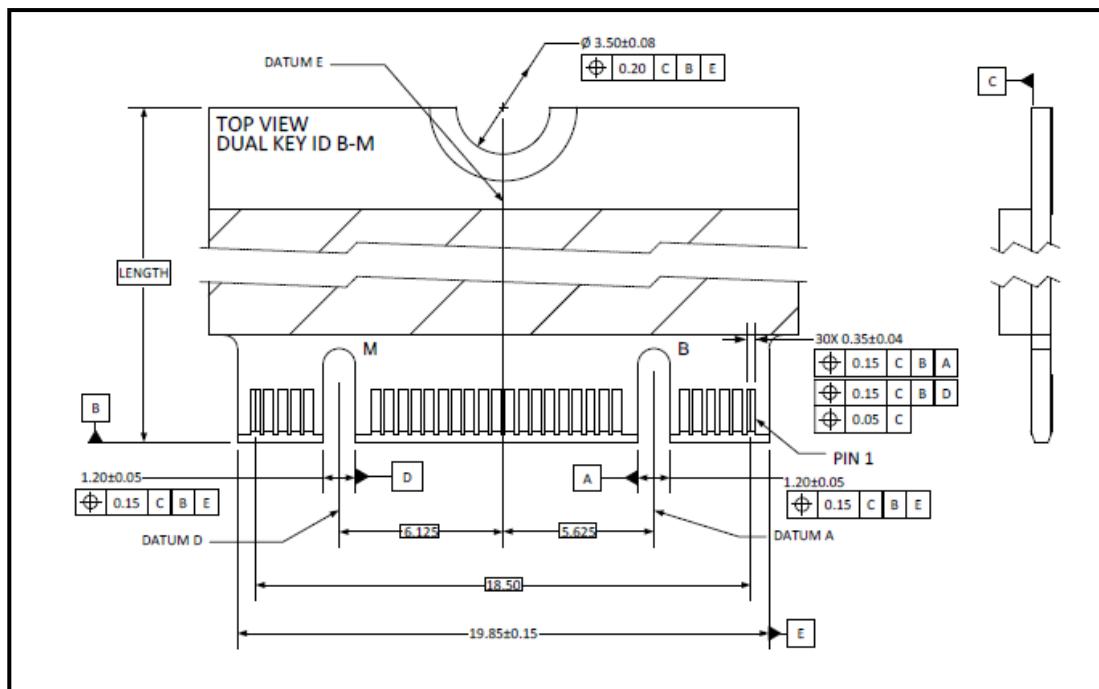


Figure 6: Signal Segment and Power Segment

4.2 Electrical Connections for M.2 (S80) 3SE2-P

A Serial ATA device may be either directly connected to a host or connected to a host through a cable. For connection via cable, the cable should be no longer than 1meter. The SATA interface has a separate connector for the power supply. Please refer to the pin description for further details.

4.3 Device Drive

No additional device drives are required. The Innodisk M.2 (S80) 3SE2-P can be configured as a boot device.

5. SMART Feature Set

Innodisk 3SE2-P series support the SMART command set and defines some vendor-specific data to report SMART attributes of SSD.

Value	Command
D0h	Read Data
D1h	Read Attribute Threshold
D2h	Enable/Disable Autosave
D3h	Save Attribute Values
D4h	Execute OFF-LINE Immediate
D5h	Read Log
D6h	Return Status
D8h	Enable SMART Operations
D9h	Disable SMART Operations
DAh	Return Status

5.1 SMART Attributes

Innodisk 3SE2-P series SMART data attributes are listed in following table.

Attribute ID (hex)	Raw Attribute Value							Attribute Name
1 (01h)	MSB	00	00	00	00	00	00	Raw Read Error Rate
5 (05h)	LSB	MSB	00	00	00	00	00	Reallocated Sector Count
9 (09h)	LSB			MSB	00	00	00	Power-on Hours
12 (0Ch)	LSB			MSB	00	00	00	Power Cycle Count
160 (A0h)	LSB			MSB	00	00	00	Uncorrectable sector count when read/write
161 (A1h)	LSB	MSB	00	00	00	00	00	Number of valid spare block
163 (A3h)	LSB	MSB	00	00	00	00	00	Number of initial invalid block
164 (A4h)	LSB	MSB	00	00	00	00	00	Total erase count
165 (A5h)	LSB			MSB	00	00	00	Maxumum erase count
166 (A6h)	LSB			MSB	00	00	00	Minimum erase count
167 (A7h)	LSB			MSB	00	00	00	Average erase count
168 (A8h)	LSB			MSB	00	00	00	Max erase count of spec
169 (A9h)	LSB			MSB	00	00	00	Reman Life (percentage)
175 (AFh)	LSB			MSB	00	00	00	Program fail count in worst die
176 (B0h)	LSB			MSB	00	00	00	Erase fail count in worst die
177 (B1h)	LSB			MSB	00	00	00	Total wear level count

178 (B2h)	LSB	MSB	00	00	00	00	Runtime invalid block count
181 (B5h)	LSB			MSB	00	00	Total program fail count
182 (B6h)	LSB	MSB	00	00	00	00	Total erase fail count
187 (BBh)	LSB			MSB	00	00	Uncorrectable error count
192 (C0h)	LSB	MSB	00	00	00	00	Power-Off Retract Count
194 (C2h)	MSB	00	00	00	00	00	Controlled temperature
195 (C3h)	LSB			MSB	00	00	Hardware ECC recovered
196 (C4h)	LSB			MSB	00	00	Reallocation event count
198 (C6h)	LSB			MSB	00	00	Uncorrectable error count off-line
199 (C7h)	LSB	MSB	00	00	00	00	UltraDMA CRC error count
225 (E1h)	LSB					MSB	Total LBAs written (each write unit = 32MB)
232 (E8h)	LSB	MSB	00	00	00	00	Available reserved space
241 (F1h)	LSB					MSB	Total LBAs written (each write unit = 32MB)
242 (F2h)	LSB					MSB	Total LBAs read (each write unit = 32MB)

6. AES Algorithm Certification

The following provides technical information about controller implementations that have been validated as confirming to the Advanced Encryption Standard (AES) Algorithm, Deterministic Random Bit Generator (DRBG) Algorithm, and Secure Hash Standard (SHS).

6.1 AES Algorithm

Val. No	Operational Environment	Val. Date	Modes/States/Key sizes/Description/Notes
2474	Cadence NC-verilog hardware simulator v10.20	May/24/2013	Using the tests found in The Advanced Encryption Standard Algorithm Validation Suite (AESAVS). This testing is performed by NVLAP accredited Cryptographic And Security Testing (CST) Laboratories. ECB (e/d; 128, 192, 256) XTS (KS: XTS_128) KS: XTS_256

6.2 DRBG Algorithm

Val. No	Operational Environment	Val. Date	Modes/States/Key sizes/Description/Notes
337	Cadence NC-verilog hardware simulator v10.20	May/24/2013	Using the tests found in The DRBG Validation Suite (DRBGVS). This testing is performed by NVLAP accredited Cryptographic And Security Testing (CST) Laboratories. HashBased DRBG: Prediction Resistance Tested: enabled and not enabled (SHA-256)

6.3 SHS Algorithm

Val. No	Operational Environment	Val. Date	Modes/States/Key sizes/Description/Notes
2093	Cadence NC-verilog hardware simulator v10.20	May/24/2013	Has been validated as confirming to the Secure Hash Algorithm specified in Federal Information Processing Standard (FIPS) 180-3, Secure Hash Standard (SHS), using tests described in the Secure Hash Algorithm Validation System (SHAVS). This testing is performed by NVLAP accredited Cryptographic And Security Testing (CST) Laboratories. SHA-256

7. Part Number Rule

CODE	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21						
	D	E	M	2	8	-	B	5	6	D	8	2	S	C	A	Q	B	-	X	X	X						
Definition																											
Code 1st (Disk)											Code 14th (Operation Temperature)																
D: Disk											C: Standard Grade (0°C ~ +70°C)																
Code 2nd (Disk)											W: Industrial Grade (-40°C ~ +85°C)																
E: Embedded series																											
Code 3rd ~5th (Form factor)											Code 15th (Internal control)																
M28: M.2-SATA Type 2280-D2-B-M											A~Z: PCB version.																
Code 7th ~9th (Capacity)											Code 16th (Channel of data transfer)																
08G: 8GB					64G: 64GB						D: Dual Channels																
16G: 16GB					A28: 128GB						Q: Quad Channels																
32G: 32GB					B56: 256GB																						
Code 10th ~12th (Controller)											Code 17th (Flash Type)																
D82: M.2 (S80) 3SE2-P with AES engine											B: Toshiba SLC																
Code 13th (Flash mode)											Code 19th~21st (Customize code)																
S: Synchronous Flash																											

8. Appendix

REACH



宜鼎國際股份有限公司
Innodisk Corporation
REACH Declaration

Tel:(02)7703-3000 Fax:(02) 7703-3555 Internet: <http://www.innodisk.com/>

We hereby confirm that the product(s) delivered to

Innodisk P/N	Description
All Innodisk EM FLASH Products	

- contain(s) no hazardous substances or constituents exceeding the defined threshold 0.1 % by weight in homogenous material if not otherwise specified, as described in the candidate list table currently including 201 substances and shown on the ECHA website (<http://echa.europa.eu/de/candidate-list-table>).
- contain(s) one or more hazardous substances or constituents exceeding 0.1 % by weight in homogenous material if not otherwise specified in candidate list table. Where the threshold value is exceeded, the substances in question are to be declared in accompanying Appendix A.
- Comply with REACH Annex XVII.

Guarantor

Company name 公司名稱：Innodisk Corporation 宜鼎國際股份有限公司

Company Representative 公司代表人：Randy Chien 簡川勝

Company Representative Title 公司代表人職稱：Chairman 董事長

Date 日期：2019 / 07 / 24

RoHS

**宜鼎國際股份有限公司
Innodisk Corporation**

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Tel:(02)7703-3000 Fax:(02) 7703-3355 Internet: <http://www.innodisk.com/>**RoHS 自我宣告書 (RoHS Declaration of Conformity)****Manufacturer Product: All Innodisk EP products**

一、 宜鼎國際股份有限公司（以下稱本公司）特此保證售予貴公司之所有產品，皆符合歐盟 2011/65/EU 及(EU) 2015/863 關於 RoHS 之規範要求。

Innodisk Corporation declares that all products sold to the company, are complied with European Union RoHS Directive (2011/65/EU) and (EU) 2015/863 requirement.

二、 本公司同意因本保證書或與本保證書相關事宜有所爭議時，雙方宜友好協商，達成協議。

Innodisk Corporation agrees that both parties shall settle any dispute arising from or in connection with this Declaration of Conformity by friendly negotiations.

Name of hazardous substance	Limited of RoHS ppm (mg/kg)
鉛 (Pb)	< 1000 ppm
汞 (Hg)	< 1000 ppm
鎘 (Cd)	< 100 ppm
六價鉻 (Cr 6+)	< 1000 ppm
多溴聯苯 (PBBs)	< 1000 ppm
多溴二苯醚 (PBDEs)	< 1000 ppm
鄰苯二甲酸二(2-乙基己基)酯 (DEHP)	< 1000 ppm
鄰苯二甲酸丁酯苯甲酯 (BBP)	< 1000 ppm
鄰苯二甲酸二丁酯 (DBP)	< 1000 ppm
鄰苯二甲酸二異丁酯 (DIBP)	< 1000 ppm

立 保 證 書 人 (Guarantor)Company name 公司名稱：Innodisk Corporation 宜鼎國際股份有限公司Company Representative 公司代表人：Randy Chien 簡川勝Company Representative Title 公司代表人職稱：Chairman 董事長Date 日期：2018 / 07 / 01

CE**VERIFICATION OF COMPLIANCE**

This Verification of Compliance is hereby issued to the below named company. The test results of this report relate only to the tested sample identified in this report.

Technical Standard: EMC DIRECTIVE 2014/30/EU
(EN55032 / EN55024)

General Information

Applicant: innodisk Corporation
5F., No. 237, Sec. 1, Datong Rd., Xizhi Dist.,
New Taipei City 22161, Taiwan (R.O.C.)

Product Description

EUT Description: M.2
Brand Name: innodisk
Model Number: M.2 (S80) 3S*&-&
S:Flash type: (S:SLC, I:iSLC, M:MLC, T:3D TLC, A~Z:Others);
*:Product line: (E:Embedded, G:EverGreen, R:InnoRobust, S:Server, V:InnoREC, A~Z:Others);
z:Product Generation: (empty, 0~9);
&:Product line: (empty, P:Plus)

Measurement Standard

EN 55032: 2012 / AC: 2013
CISPR 32: 2012
EN 61000-3-2: 2014
EN 61000-3-3: 2013
EN 55024: 2010 + A1: 2015
(IEC 61000-4-2: 2008; IEC 61000-4-3: 2006 + A1: 2007 + A2: 2010; IEC 61000-4-4: 2012;
IEC 61000-4-5: 2014; IEC 61000-4-6: 2013; IEC 61000-4-8: 2009; IEC 61000-4-11: 2004)

Measurement Facilities

Xindian Lab.: Compliance Certification Services Inc.
No. 163-1, Jhongsheng Rd., Xindian Dist., New Taipei City, 23151 Taiwan.
Tel: +886-2-22170894 / Fax: +886-2-22171029

This device has been shown to be in compliance with and was tested in accordance with the measurement procedures specified in the Standards & Specifications listed above and as indicated in the measurement report number: T170504D05-E

Sam Hu / Assistant Manager
Date: May 10, 2017

CCSRF程翹科技股份有限公司
Compliance Certification Services Inc.

FCC**VERIFICATION OF COMPLIANCE**

This Verification of Compliance is hereby issued to the below named company. The test results of this report relate only to the tested sample identified in this report.

**Technical Standard: FCC Part 15 Class B
IC ICES-003**

General Information

Applicant: Innodisk Corporation
5F., No. 237, Sec. 1, Datong Rd., Xizhi Dist.,
New Taipei City 22161, Taiwan (R.O.C)

Product Description

EUT Description: M.2
Brand Name: Innodisk
Model Number: M.2 (S80) 3SE2-P-
\$:Flash type: (S:SLC, I:iSLC, M:MLC, T:3D TLC, A-Z:Others);
#:Product line: (E:Embedded, G:EverGreen, R:InnoRobust, S:Server, V:InnoREC, A-Z:Others);
#:Product Generation: (empty, 0~9);
&:Product line: (empty, P:Plus)

Measurement Facilities

Xindian Lab.: *Compliance Certification Services Inc.*
No. 163-1, Zhongsheng Rd., Xindian Dist., New Taipei City, 23151 Taiwan.
Tel: +886-2-22170894 / Fax: +886-2-22171029

This device has been shown to be in compliance with and was tested in accordance with the measurement procedures specified in the Standards & Specifications listed above and as indicated in the measurement report number: T170504D05-D

Sam Hu / Assistant Manager

Date: May 10, 2017

CCSRF
程智科技股份有限公司
Compliance Certification Services Inc.